Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/621,448	OHISHI ET AL.
Examiner	Art Unit
Steven Kau	2625

SEARCHED				
Class	Subclass	Date	Examiner	
358	1.15	6/12/2007	SK	
463	42	6/12/2007	SK	
705	21	6/12/2007	sĸ	
706	908, 916	6/12/2007	SK	
725	220-225	6/12/2007	sĸ	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	1		

SEARCH N (INCLUDING SEAR)
	DATE	EXMR
EAST Search	6/12/2007	sĸ
US-PGPUB Search	6/12/2007	sĸ
Inventor name search	6/12/2007	sĸ
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